

Group Art Unit: 2886
Confirmation No.: 3799
Examiner: Nur, A.

Atty. Ref.: F04-018US

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants : Tohru Koike et al.
Appl. No. : 10/575,714
Filed : May 8, 2006
For : METHOD FOR MEASURING A SURFACE PLASMON
RESONANCE AND NOBLE METAL COMPOUND USED FOR THE
SAME

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

FIFTH INFORMATION DISCLOSURE STATEMENT

Sir:

The above-identified US patent application has related applications pending in Australia, Europe and Japan. Office Action have issued recently in connection with these three related applications. Copies of all three Office Actions are attached.

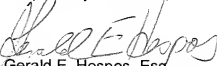
The Examiner will note that the Australian Office Action issued on February 17, 2010 and cited a total of eight references. The first seven references already are of record in the above captioned US patent application. However, the Australian Office Action also cites US Patent No. 5,376,556. The relevancy of this reference as perceived by the Australian Examiner is explained on page 3 of the Australian Office Action.

The European Office Action issued on March 4, 2010. The European Examiner cited eight references as being relevant. All eight references cited in the European application had been made of record in the United States.

The Japanese Office Action issued on April 7, 2010. The Japanese Examiner cited three Japanese references as being relevant. JP6-174723 corresponds to EP 0 587 008. The European equivalent also is listed on the attached copy of Form PTO/SB/08A and a copy of that English language publication is attached. The other two Japanese references do not appear to have English language equivalent, but copies of the references are attached along with their English language abstract.

The Examiner is requested to consider these references during the examination and to make the references of record.

Respectfully submitted,



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